TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOSIII)

# **TPCS8210**

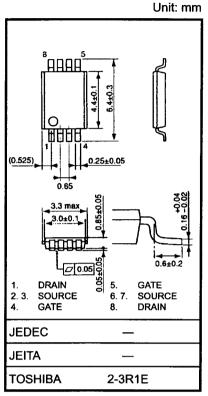
### **Lithium Ion Battery Applications**

- Has a small footprint.
- Low drain-source ON resistance: RDS (ON) = 19 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 9.2 \text{ S (typ.)}$
- Low leakage current:  $IDSS = 10 \mu A \text{ (max) (VDS} = 20 \text{ V)}$
- Enhancement-mode:  $V_{th} = 0.5 \sim 1.2 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 200 \mu\text{A})$
- Common drain

### **Maximum Ratings (Ta = 25°C)**

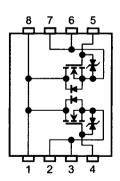
Char	acteristics	Symbol	Rating	Unit	
Drain-source vol	tage	V <sub>DSS</sub>	20	· V	
Drain-gate voltag	ge (R <sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub>	20	V	
Gate-source voltage		V <sub>GSS</sub>	±12	V	
	DC (Note 1)	I <sub>D</sub>	5	Α	
Drain current	n-gate voltage $(R_{GS} = 20 \text{ k}\Omega)$ VDGR  p-source voltage VGSS  DC (Note 1) ID  Pulse (Note 1) IDP  Single-device operation (Note 3a) PD (1)  Single-device value at dual operation (Note 3b)  In power pation (Note 3b)  Single-device value at dual operation (Note 3a)  Single-device value operation (Note 3b)  Single-device value operation (Note 3b)  Single-device value at dual operation (Note 3b)  Single-device value at dual operation (Note 3b)  EAS	20	^		
Drain power		P <sub>D (1)</sub>	1.1	w	
dissipation (t = 10 s) (Note 2a)	at dual operation	P <sub>D (2)</sub>	0.75		
Drain power dissipation (t = 10 s) (Note 2b)		P <sub>D (1)</sub>	0.6		
	at dual operation	P <sub>D (2)</sub>	0.35	W	
Single pulse avalanche energy (Note 4)		E <sub>AS</sub>	32.5	mJ	
Avalanche curre	nt	I <sub>AR</sub>	5	Α	
Repetitive avalanche energy Single-device value at dual operation (Note 2a, 3b, 5)		E <sub>AR</sub>	0.075	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage tempera	ture range	T <sub>stg</sub>	-55~150	°C	

Note: (Note 1), (Note 2), (Note 3), (Note 4), (Note 5) Please see next page. This transistor is an electrostatic sensitive device. Please handle with caution.



Weight: 0.035 g (typ.)

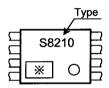
### **Circuit Configuration**



#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit		
	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	114	°C/W	
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	Rth (ch-a) (2)	167		
The second secon	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	208		
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th</sub> (ch-a) (2)	R <sub>th (ch-a) (2)</sub> 357		

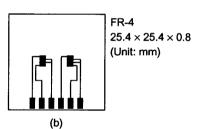
### Marking (Note 6)



Note 1: The channel temperature should not exceed 150°C.

#### Note 2:

- a) Device mounted on a glass-epoxy board (a)
  - FR-4 25.4 × 25.4 × 0.8 (Unit: mm)
- b) Device mounted on a glass-epoxy board (b)



#### Note 3:

- The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.).
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.).
- Note 4:  $V_{DD}$  = 16 V,  $T_{ch}$  = 25°C (initial), L = 1.0 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 5 A
- Note 5: Repetitive rating; pulse width limited by max channel temperature.
- Note 6: o on lower right of the marking indicates Pin 1.

  \* shows lot number. (Year of manufacture: last decimal digit of the year of manufacture, Month of manufacture: January to December are denoted by letters A to L respectively)

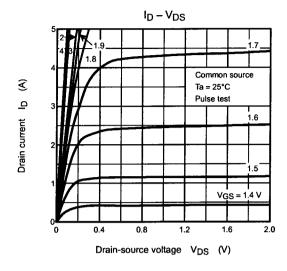


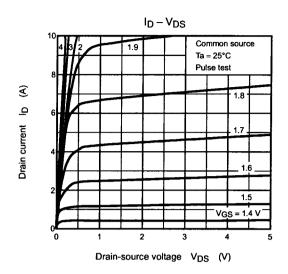
## **Electrical Characteristics (Ta = 25°C)**

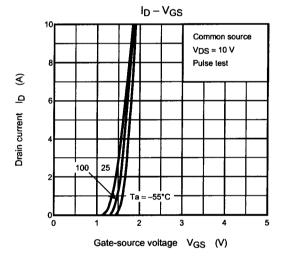
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I <sub>GSS</sub>	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_		±10	μА
Drain cut-OFF cu	ırrent	Ipss	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	10	μА
Drain-source breakdown voltage		V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	20	_	_	_
		V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	8	_		
Gate threshold v	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 200 μA	0.5		1.2	٧
			$V_{GS} = 2.0 \text{ V}, I_D = 3.5 \text{ A}$	_	34	60	mΩ
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 2.5 V, I <sub>D</sub> = 3.5 A		26	40	
			V <sub>GS</sub> = 4.0 V, I <sub>D</sub> = 4.0 A	-	19	30	
Forward transfer admittance		Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.5 A	4.6	9.2		S
Input capacitance		C <sub>iss</sub>		_	1280	_	
Reverse transfer	capacitance	C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		130	_	pF
Output capacitance		Coss			150	_	
	Rise time	t <sub>r</sub>	$V_{GS}$ $\stackrel{5}{\circ}$ $\stackrel{V}{\downarrow}$ $\stackrel{I_{D}}{\downarrow}$ $\stackrel{2.5}{\circ}$ $\stackrel{A}{\circ}$ $\stackrel{A}{\circ}$ $\stackrel{V}{\circ}$ $\stackrel{A}{\circ}$		4.5	_	
Output capacitanc	Turn-ON time	t <sub>on</sub>		_	11	-	ns
	Fall time	t <sub>f</sub>		_	7.3		
	Turn-OFF time	toff			33	_	
Total gate charge (gate-source plus gate-drain)		Qg			15		_
Gate-source charge 1		Q <sub>gs1</sub>	$V_{DD} \approx 16 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 5 \text{ A}$	_	3.3	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	3.5	_	

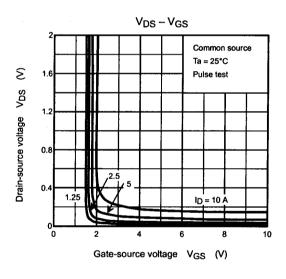
### **Source-Drain Diode Ratings and Characteristics (Ta = 25°C)**

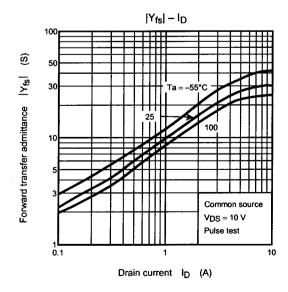
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	_	_	_	20	Α
Diode forward voltage		V <sub>DSF</sub>	I <sub>DR</sub> = 5 A, V <sub>GS</sub> = 0 V		_	-1.2	٧

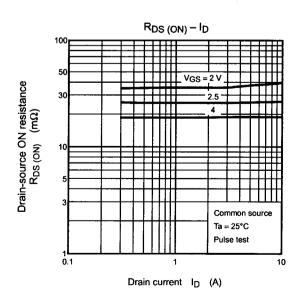


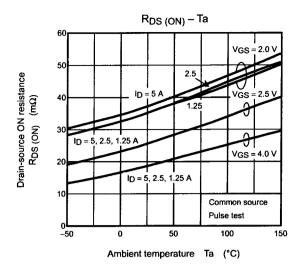


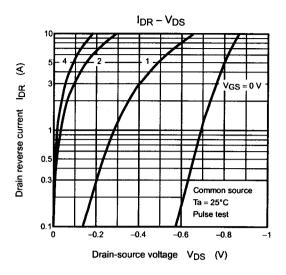


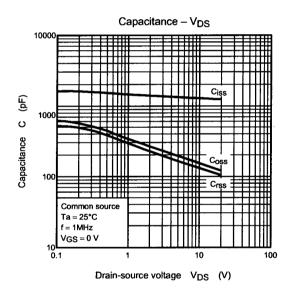


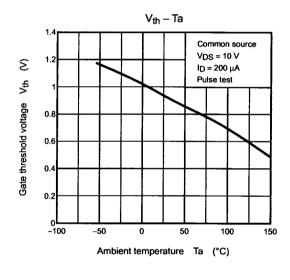


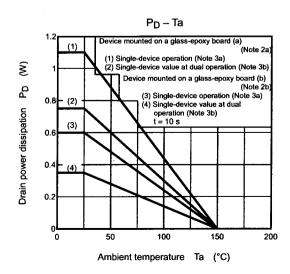


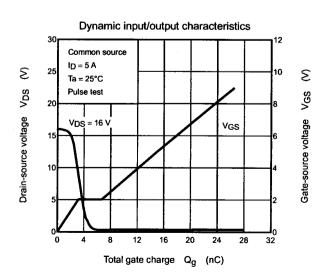


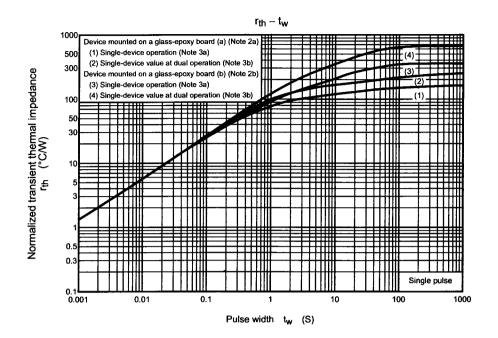


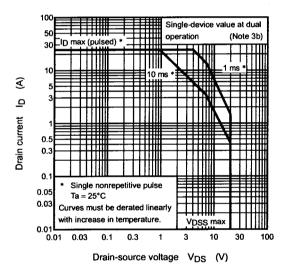












#### **RESTRICTIONS ON PRODUCT USE**

000707EAA

- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
  In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- The information contained herein is presented only as a guide for the applications of our products. No
  responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other
  rights of the third parties which may result from its use. No license is granted by implication or otherwise under
  any intellectual property or other rights of TOSHIBA CORPORATION or others.
- The information contained herein is subject to change without notice.